

COMPLIANT

HALOGEN FREE

AM4990N-VB Datasheet

Dual N-Channel 100-V (D-S) MOSFET

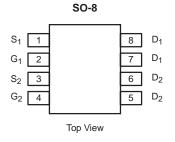
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)		
100	0.063 at V _{GS} = 10 V	5.8	9 nC		
100	0.084 at V _{GS} = 6 V	4.8	9110		

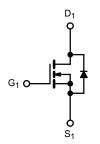
FEATURES

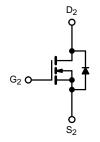
- Halogen-free According to IEC 61249-2-21 Available
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

- High Frequency Boost Converter
- LED Backlight for LCD TV







N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	- A - 20 0,			11-14	
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	100	v		
Gate-Source Voltage		V_{GS}	± 20		
	T _C = 25 °C		5.8		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1_	4.4		
Continuous Brain Current (1) = 130 °C)	T _A = 25 °C	l _D	3.4 ^{a, b}		
	T _A = 70 °C		2.5 ^{a, b}	Α	
Pulsed Drain Current	I _{DM}	20			
Continuous Source-Drain Diode Current	T _C = 25 °C	la	5		
Continuous Source-Diam Diode Current	T _A = 25 °C	ls –	2.1 ^{a, b}		
Single Avalanche Current	L = 0.1 mH	I _{AS}	19		
Single Avalanche Energy	Energy		18	mJ	
	T _C = 25 °C		5		
Maximum Dawar Dissination	T _C = 70 °C	P _D	3.2	w	
Maximum Power Dissipation	T _A = 25 °C	LD	2.5 ^{a, b}	VV	
	T _A = 70 °C		1.6 ^{a, b}		
Operating Junction and Storage Temperature	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, c}	t ≤ 10 s	R_{thJA}	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	21	0/ **		

Notes

- a. Surface Mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 85 °C/W.
- d. $T_C = 25$ °C.

服务热线:400-655-8788

1



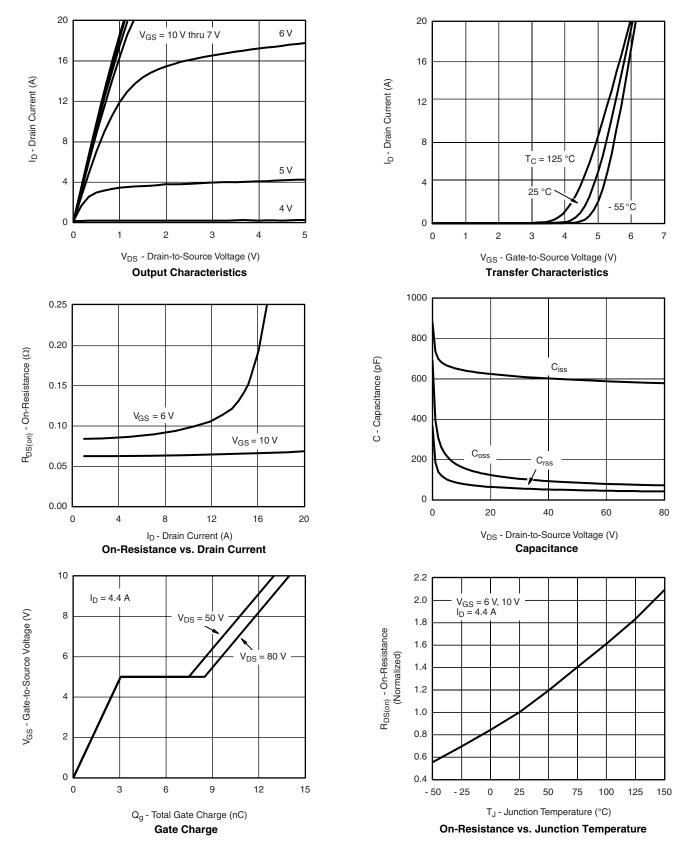
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			I.		I.	•	
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		120		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 9			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2		4.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Vallana Busin Oursell	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
		$V_{GS} = 10 \text{ V}, I_D = 3.4 \text{ A}$	0.063			<u> </u>	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 6 \text{ V}, I_D = 2.8 \text{ A}$		0.084		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 3.4 A		10		S	
Dynamic ^b				I.			
Input Capacitance	C _{iss}			600			
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		90		pF	
Reverse Transfer Capacitance	C _{rss}			50			
Tabal Oaks Observes	Qg	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3.4 \text{ A}$		13.5	20		
Total Gate Charge				9	13.5	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 3.4 \text{ A}$		3			
Gate-Drain Charge	Q_{gd}			4.6			
Gate Resistance	R_{g}	f = 1 MHz		1		Ω	
Turn-On Delay Time	t _{d(on)}			15	25		
Rise Time	t _r	V_{DD} = 50 V, R_L = 14.3 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 3.5$ A, $V_{GEN}=6$ V, $R_g=1$ Ω		12	20		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			10	15	ns -	
Rise Time	t _r	V_{DD} = 50 V, R_L = 14.3 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 3.5$ A, V_{GEN} = 10 V, R_g = 1 Ω		15	25		
Fall Time	t _f			10	15	1	
Drain-Source Body Diode Characteristi	cs					•	
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			5	_	
Pulse Diode Forward Current	I _{SM}				20	Α	
Body Diode Voltage	V _{SD}	I _S = 3.5 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			45	70	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 3.5 A, dI/dt = 100 A/μs, T _J = 25 °C		80	120	nC	
Reverse Recovery Fall Time	ta	1 _F = 0.5 Λ, αι/αι = 100 Α/μs, 1 _J = 25 °C		33		20	
Reverse Recovery Rise Time	t _b			12		ns	

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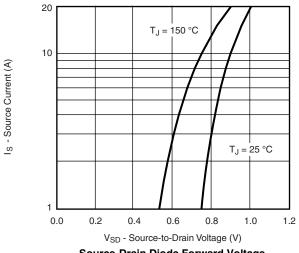
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

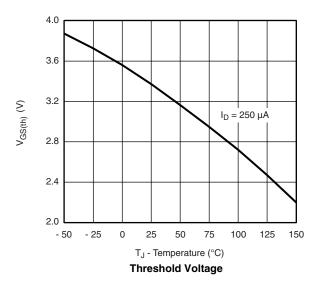


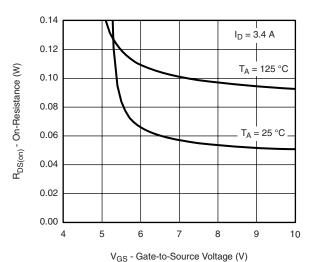




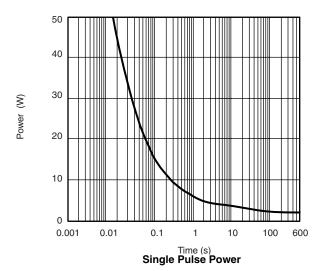


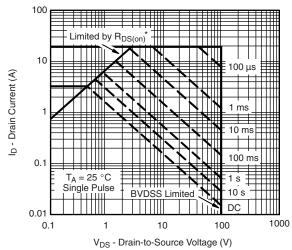
Source-Drain Diode Forward Voltage





On-Resistance vs. Gate-to-Source Voltage

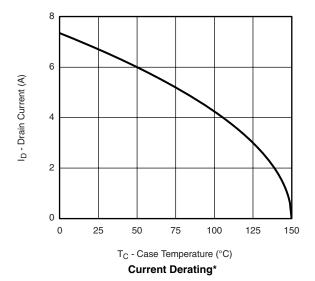


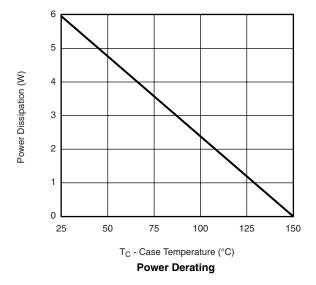


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

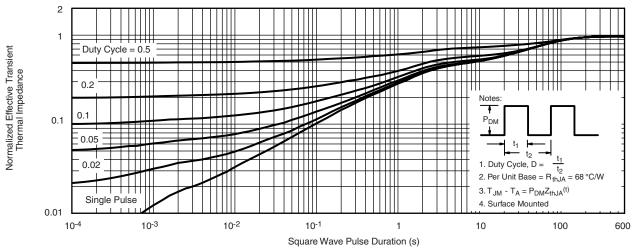




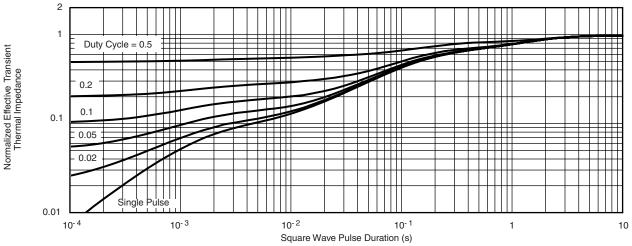


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





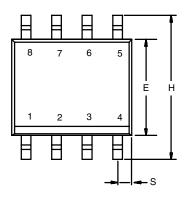
Normalized Thermal Transient Impedance, Junction-to-Ambient

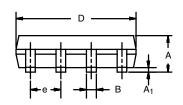


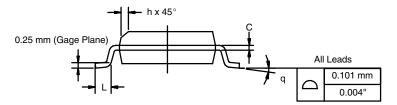
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







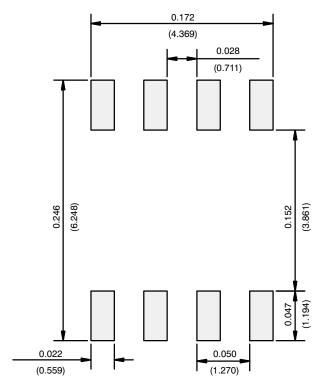
	MILLIM	IETERS	INC	INCHES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. J. 11-Sep-06						

DWG: 5498

8



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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